

Issue Classification			Application/Control No.	Applicant(s)/Patent under Reexamination	
			10/006,669	OGAWA ET AL.	
Examiner			Art Unit		
Gabriel L. Chu			2114		

ISSUE CLASSIFICATION

ORIGINAL			CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
714	8	714	710					
INTERNATIONAL CLASSIFICATION								
G	D	E	F	11	/			
					/			
					/			
					/			
<i>reilly</i> <i>5/26/05</i> (Assistant Examiner) (Date)			<i>Robert H. Beausoliel</i> ROBERT BEAUSOLIEL SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2100 (Primary Examiner) (Date) <i>5/26/05</i>			Total Claims Allowed: 5		
<i>D. J. Dabbs</i> <i>5/26/05</i> (Legal Instruments Examiner) (Date)						O.G. Print Claim(s) <i>1</i>	O.G. Print Fig. <i>1</i>	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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5		35	65	95	125	155	185
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9		39	69	99	129	159	189
10		40	70	100	130	160	190
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12		42	72	102	132	162	192
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